ADC1002S020

Single 10 bits ADC, up to 20 MHz Rev. 02 — 13 August 2008

Product data sheet

1. **General description**

The ADC1002S020 is a 10-bit high-speed Analog-to-Digital Converter (ADC) for professional video and other applications. It converts with 3.0 V to 5.25 V operation the analog input signal into 10-bit binary-coded digital words at a maximum sampling rate of 20 MHz. All digital inputs and outputs are CMOS compatible. A standby mode allows a reduction of the device power consumption to 4 mW.

Features 2.

- 10-bit resolution
- 3.0 V to 5.25 V operation
- Sampling rate up to 20 MHz
- DC sampling allowed
- High signal-to-noise ratio over a large analog input frequency range (9.3 effective bits at 1.0 MHz; full-scale input at $f_{clk} = 20$ MHz)
- In-Range (IR) CMOS output
- CMOS/Transistor-Transistor Logic (TTL) compatible digital inputs and outputs
- External reference voltage regulator
- Power dissipation only 53 mW (typical value)
- Low analog input capacitance, no buffer amplifier required
- Standby mode
- No sample-and-hold circuit required

Applications

- Video data digitizing
- Camera
- Camcorder
- Radio communication
- Barcode scanner



4. Quick reference data

Table 1. Quick reference data

 $V_{DDA}=V7$ to V9=3.3 V; $V_{DDD}=V4$ to V3=V18 to V19=3.3 V; $V_{DDO}=V20$ to V21=3.3 V; V_{SSA} , V_{SSD} and V_{SSO} shorted together; $V_{i(p-p)}=1.83$ V; $C_L=20$ pF; $T_{amb}=0$ °C to 70 °C; typical values measured at $T_{amb}=25$ °C unless otherwise specified.

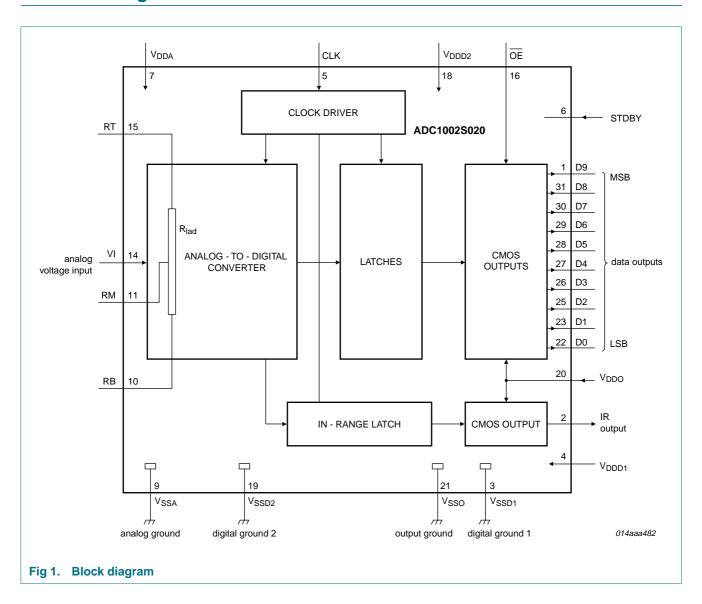
		•				
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DDA}	analog supply voltage		3.0	3.3	5.25	V
V_{DDD1}	digital supply voltage 1		3.0	3.3	5.25	V
V_{DDD2}	digital supply voltage 2		3.0	3.3	5.25	V
V_{DDO}	output supply voltage		3.0	3.3	5.25	V
I _{DDA}	analog supply current		-	7.5	10	mA
I _{DDD}	digital supply current		-	7.5	10	mA
I _{DDO}	output supply current	$f_{clk} = 20 \text{ MHz};$ ramp input; $C_L = 20 \text{ pF}$	-	1	2	mA
INL	integral non-linearity	ramp input; see Figure 6	-	±1	±2	LSB
DNL	differential non-linearity	ramp input; see Figure 7	-	±0.25	±0.7	LSB
f _{clk(max)}	maximum clock frequency		20	-	-	MHz
P _{tot}	total power dissipation	operating; V _{DDD} = 3.3 V	-	53	73	mW
		standby mode	-	4	-	mW

5. Ordering information

Table 2. Ordering information

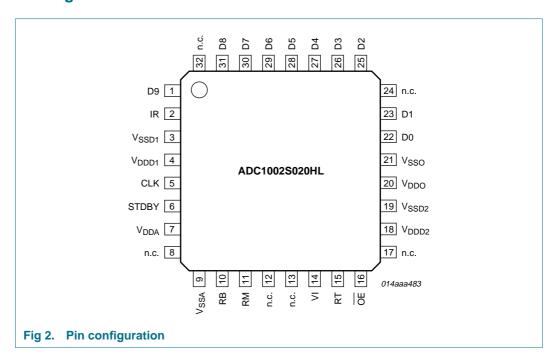
Type number	Package		
	Name	Description	Version
ADC1002S020HL	LQFP32	plastic low profile quad flat package; 32 leads; body $5 \times 5 \times 1.4$ mm	SOT401-1

6. Block diagram



7. Pinning information

7.1 Pinning



7.2 Pin description

Table 3. Pin description

Symbol	Pin	Description
D9	1	data output; bit 9 (Most Significant Bit (MSB))
IR	2	in-range data output
V _{SSD1}	3	digital ground 1
V_{DDD1}	4	digital supply voltage 1 (3.0 V to 5.25 V)
CLK	5	clock input
STDBY	6	standby mode input
V_{DDA}	7	analog supply voltage (3.0 V to 5.25 V)
n.c.	8	not connected
V_{SSA}	9	analog ground
RB	10	reference voltage BOTTOM input
RM	11	reference voltage MIDDLE input
n.c.	12	not connected
n.c.	13	not connected
VI	14	analog voltage input
RT	15	reference voltage TOP input
ŌĒ	16	output enable input (active LOW)
n.c.	17	not connected
V_{DDD2}	18	digital supply voltage 2 (3.0 V to 5.25 V)

 Table 3.
 Pin description ...continued

Symbol	Pin	Description
V _{SSD2}	19	digital ground 2
V_{DDO}	20	positive supply voltage for output stage (3.0 V to 5.25 V)
V_{SSO}	21	output stage ground
D0	22	data output; bit 0 (Least Significant Bit (LSB))
D1	23	data output; bit 1
n.c.	24	not connected
D2	25	data output; bit 2
D3	26	data output; bit 3
D4	27	data output; bit 4
D5	28	data output; bit 5
D6	29	data output; bit 6
D7	30	data output; bit 7
D8	31	data output; bit 8
n.c.	32	not connected

8. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

		,	,		
Symbol	Parameter	Conditions	Min	Max	Unit
V_{DDA}	analog supply voltage		<u>[1]</u> –0.3	+7.0	V
V_{DDD}	digital supply voltage		<u>[1]</u> –0.3	+7.0	V
V_{DDO}	output supply voltage		[<u>1]</u> –0.3	+7.0	V
ΔV_{DD}	supply voltage difference	$V_{DDA} - V_{DDD}$ $V_{DDD} - V_{DDO}$ $V_{DDA} - V_{DDO}$	-0.1	+4.0	V
VI	input voltage	referenced to V _{SSA}	-0.3	+7.0	V
$V_{i(a)(p-p)}$	peak-to-peak analog input voltage	referenced to V _{SSD}	-	V_{DDD}	V
Io	output current		-	10	mA
T _{stg}	storage temperature		-55	+150	°C
T _{amb}	ambient temperature		-20	+75	°C
Tj	junction temperature		-	150	°C

^[1] The supply voltages V_{DDA} , V_{DDD} and V_{DDO} may have any value between -0.3 V and +7.0 V provided that the supply voltage ΔV_{DD} remains as indicated.

9. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Condition	Value	Unit
$R_{th(j-a)}$	thermal resistance from junction to ambient	in free air	90	K/W

10. Characteristics

Table 6. Characteristics

 $V_{DDA} = V7$ to V9 = 3.3 V; $V_{DDD} = V4$ to V3 = V18 to V19 = 3.3 V; $V_{DDO} = V20$ to V21 = 3.3 V; V_{SSA} , V_{SSD} and V_{SSO} shorted together; $V_{i(p-p)} = 1.83$ V; $C_L = 20$ pF; $T_{amb} = 0$ °C to 70 °C; typical values measured at $T_{amb} = 25$ °C unless otherwise specified.

<i>ъреспіеа.</i>						
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Supplies						
V_{DDA}	analog supply voltage		3.0	3.3	5.25	V
V_{DDD1}	digital supply voltage 1		3.0	3.3	5.25	V
V_{DDD2}	digital supply voltage 2		3.0	3.3	5.25	V
V_{DDO}	output supply voltage		3.0	3.3	5.25	V
ΔV_{DD}	supply voltage difference	$\begin{aligned} &V_{DDA}-V_{DDD;}V_{DDD}-V_{DDO};\\ &V_{DDA}-V_{DDO} \end{aligned}$	-0.2	-	+0.2	V
I_{DDA}	analog supply current		-	7.5	10	mA
I_{DDD}	digital supply current		-	7.5	10	mA
I _{DDO}	output supply current	f_{clk} = 20 MHz; ramp input; C_L = 20 pF	-	1	2	mA
P _{tot}	total power dissipation	operating; $V_{DDD} = 3.3 \text{ V}$	-	53	73	mW
		standby mode	-	4	-	mW
Inputs						
Clock input	CLK (Referenced to V _{SSD});	<u>1]</u>				
V_{IL}	LOW-level input voltage		0	-	$0.3 V_{DDD}$	V
V _{IH} HIGH-level input voltage	$V_{DDD} \le 3.6 \text{ V}$	$0.6 V_{DDD}$	-	V_{DDD}	V	
		V _{DDD} > 3.6 V	$0.7 V_{DDD}$	-	V_{DDD}	V
I _{IL}	LOW-level input current	$V_{CLK} = 0.3 V_{DDD}$	-1	0	+1	μΑ
I _{IH}	HIGH-level input current	$V_{CLK} = 0.7 V_{DDD}$	-	-	5	μΑ
Zi	input impedance	f _{clk} = 20 MHz	-	4	-	$k\Omega$
Ci	input capacitance	f _{clk} = 20 MHz	-	3	-	pF
Inputs OE a	and STDBY (Referenced to	V _{SSD}); see <u>Table 7</u> and <u>8</u>				
V _{IL}	LOW-level input voltage		0	-	$0.3 V_{DDD}$	V
V _{IH}	HIGH-level input voltage	$V_{DDD} \le 3.6 \text{ V}$	$0.6 V_{DDD}$	-	V_{DDD}	V
		V _{DDD} > 3.6 V	$0.7 V_{DDD}$	-	V_{DDD}	V
I _{IL}	LOW-level input current	$V_{IL} = 0.3 V_{DDD}$	-1	-	-	μΑ
I _{IH}	HIGH-level input current	$V_{IH} = 0.7 V_{DDD}$	-	-	1	μΑ
Analog inpu	ut VI (Referenced to V _{SSA});					
I _{IL}	LOW-level input current	$V_I = V_{RB}$	-	0	-	μΑ
I _{IH}	HIGH-level input current	$V_I = V_{RT}$	-	35	-	μΑ
Zi	input impedance	f _i = 1 MHz	-	5	-	kΩ
Ci	input capacitance	f _i = 1 MHz	-	8	-	pF
Reference	voltages for the resistor la	adder; see <u>Table 8</u>				
V _{RB}	voltage on pin RB		1.1	1.2	-	٧
V _{RT}	voltage on pin RT		3.0	3.3	V_{DDA}	V

 Table 6.
 Characteristics ...continued

 $V_{DDA} = V7$ to V9 = 3.3 V; $V_{DDD} = V4$ to V3 = V18 to V19 = 3.3 V; $V_{DDO} = V20$ to V21 = 3.3 V; V_{SSA} , V_{SSD} and V_{SSO} shorted together; $V_{i(p-p)} = 1.83$ V; $C_L = 20$ pF; $T_{amb} = 0$ °C to 70 °C; typical values measured at $T_{amb} = 25$ °C unless otherwise specified.

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V _{ref(dif)}	differential reference voltage	$V_{RT} - V_{RB}$		1.9	2.1	3.0	V
I _{ref}	reference current			-	7.2	-	mA
R _{lad}	ladder resistance			-	290	-	Ω
TC _{Rlad}	ladder resistor			-	539	-	mΩ/K
	temperature coefficient			-	1860	-	ppm
V _{offset}	offset voltage	BOTTOM	[2]	-	135	-	mV
		TOP	[2]	-	135	-	mV
$V_{i(p-p)}$	peak-to-peak input voltage		[3]	1.66	1.83	2.35	V
Digital outputs D9 to D0 and IR (Referenced to V _{SSD})							
V_{OL}	LOW-level output voltage	$I_O = 1 \text{ mA}$		0	-	0.5	V
V _{OH}	HIGH-level output voltage	$I_O = -1 \text{ mA}$		$V_{DDO} - 0.5$	-	V _{CCO}	V
l _{OZ}	OFF-state output current	$0.5 \text{ V} < \text{V}_{\text{O}} < \text{V}_{\text{DDO}}$		-20	-	+20	μΑ
Switching	characteristics; Clock inp	ut CLK; see Figure 4;[1]					
f _{clk(max)}	maximum clock frequency			20	-	-	MHz
t _{w(clk)H}	HIGH clock pulse width			15	-	-	ns
t _{w(clk)L}	LOW clock pulse width			15	-	-	ns
Analog sig	nal processing ($f_{clk} = 20 N$	1Hz)					
Linearity							
INL	integral non-linearity	ramp input; see Figure 6		-	±1	±2	LSB
DNL	differential non-linearity	ramp input; see Figure 7		-	±0.25	±0.7	LSB
Input set re	sponse; see <u>Figure 8^[4]</u>						
$t_{s(LH)}$	LOW to HIGH settling time	full-scale square wave		-	4	6	ns
t _{s(HL)}	HIGH to LOW settling time	full-scale square wave		-	4	6	ns
Harmonics;	see <u>Figure 9^[5]</u>						
THD	total harmonic distortion	f _i = 1 MHz		-	-63	-	dB
Signal-to-N	oise ratio; see Figure 9[5]						
S/N	signal-to-noise ratio	without harmonics; $f_i = 1 \text{ MHz}$		-	60	-	dB
Effective bit	ts; see <u>Figure 9^[5]</u>						
ENOB	effective number of bits	f _i = 300 KHz		-	9.5	-	bits
		f _i = 1 MHz		-	9.3		bits
		f _i = 3.58 MHz		-	8.0		bits

Table 6. Characteristics ... continued

 V_{DDA} = V7 to V9 = 3.3 V; V_{DDD} = V4 to V3 = V18 to V19 = 3.3 V; V_{DDO} = V20 to V21 = 3.3 V; V_{SSA} , V_{SSD} and V_{SSO} shorted together; $V_{i(p-p)}$ = 1.83 V; C_L = 20 pF; T_{amb} = 0 °C to 70 °C; typical values measured at T_{amb} = 25 °C unless otherwise specified.

ns Min 46 - 5	Тур - -	Max 5	Unit		
- 5					
	-				
	-	-			
75 \/ 0			ns		
10 V 0	12	15	ns		
15 V 8	17	20	ns		
3-state output delay times; see Figure 5					
-	14	18	ns		
-	16	20	ns		
-	16	20	ns		
-	14	18	ns		
-	-	200	ns		
-	-	500	ns		
	- -	- 14 - 16 - 16 - 14	- 14 18 - 16 20 - 14 18 - 16 20 - 16 20 - 17 200		

- [1] In addition to a good layout of the digital and analog ground, it is recommended that the rise and fall times of the clock must not be less than 1 ns.
- [2] Analog input voltages producing code 0 up to and including code 1023:
 - a) V_{offset} BOTTOM is the difference between the analog input which produces data equal to 00 and the reference voltage on pin RB (V_{RB}) at T_{amb} = 25 °C.
 - b) V_{offset} TOP is the difference between the reference voltage on pin RT (V_{RT}) and the analog input which produces data outputs equal to code 1023 at T_{amb} = 25 °C.
- [3] To ensure the optimum linearity performance of such a converter architecture the lower and upper extremities of the converter reference resistor ladder are connected to pins RB and RT via offset resistors R_{OB} and R_{OT} as shown in Figure 3.
 - a) The current flowing into the resistor ladder is $I = \frac{V_{RT} V_{RB}}{R_{OB} + R_L + R_{OT}}$ and the full-scale input range at the converter, to cover code 0

to 1023 is
$$V_I = R_L \times I_L = \frac{R_L}{R_{OB} + R_L + R_{OT}} \times (V_{RT} + V_{RB}) = 0.871 \times (V_{RT} - V_{RB})$$

- b) Since R_L, R_{OB} and R_{OT} have similar behavior with respect to process and temperature variation, the ratio $\frac{R_L}{R_{OB} + R_L + R_{OT}}$
 - will be kept reasonably constant from device to device. Consequently variation of the output codes at a given input voltage depends mainly on the difference $V_{RT} V_{RB}$ and its variation with temperature and supply voltage. When several ADCs are connected in parallel and fed with the same reference source, the matching between each of them is optimized.
- [4] The analog input settling time is the minimum time required for the input signal to be stabilized after a sharp full-scale input (square wave signal) in order to sample the signal and obtain correct output data.
- [5] Effective bits are obtained via a Fast Fourier Transform (FFT) treatment taking 8000 acquisition points per equivalent fundamental period. The calculation takes into account all harmonics and noise up to half the clock frequency (Nyquist frequency). Conversion to SIgnal-to-Noise And Distortion (SINAD) ratio: SINAD = ENOB × 6.02 + 1.76 dB.
- [6] Output data acquisition: the output data is available after the maximum delay time of t_{d(o)}.

11. Additional information relating to Table 6

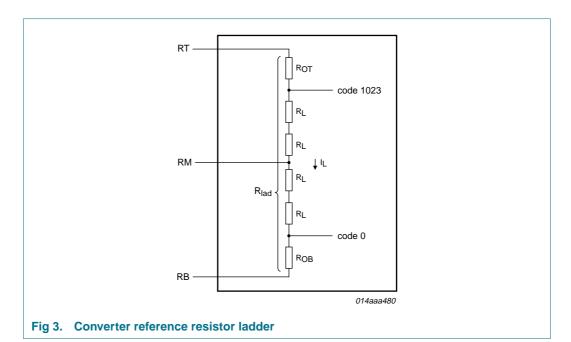


Table 7. Mode selection

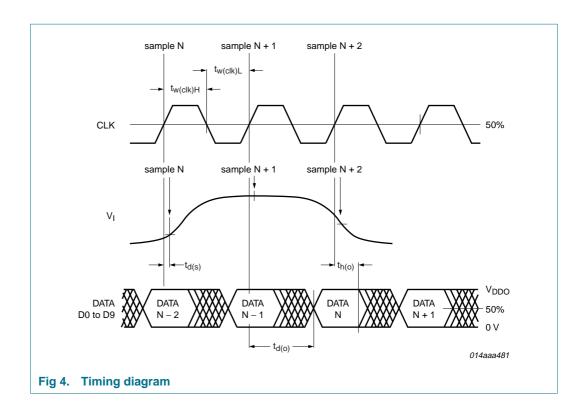
OE	D9 to D0	IR
1	high impedance	high impedance
0	active; binary	active

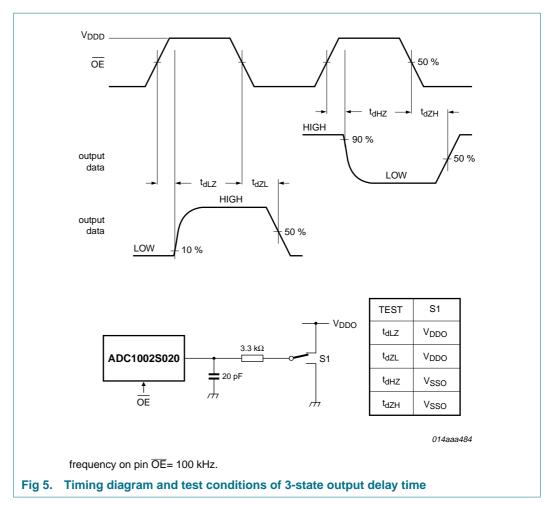
Table 8. Standby selection

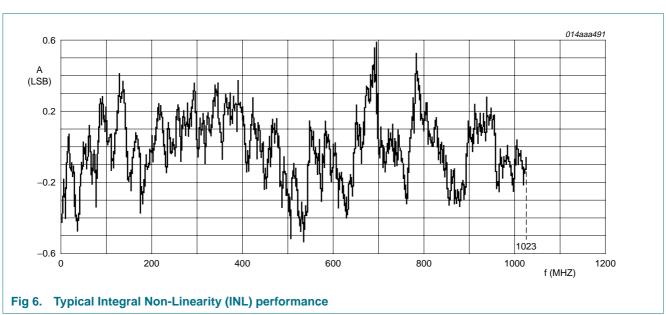
STBY	D9 to D0	I _{CCA} + I _{CCD}
1	last logic state	1.2 mA (typical value)
0	active	15 mA (typical value)

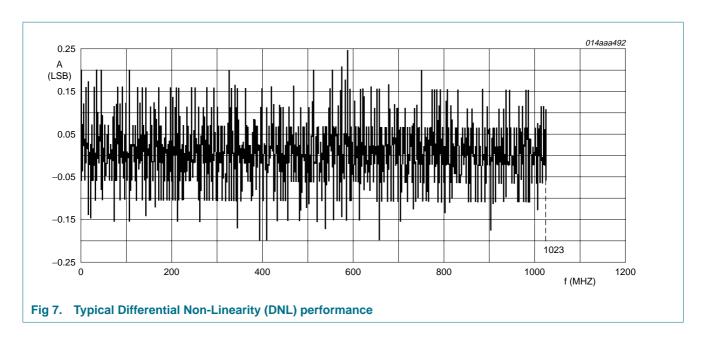
Table 9. Output coding and input voltage (typical values; referenced to V_{SSA})

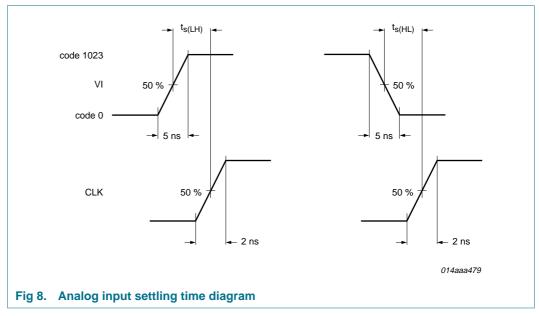
Code	$V_{i(a)(p-p)}$ (V)	IR	Binary outputs D9 to D0
Underflow	< 1.335	0	00 0000 0000
0	1.335	1	00 0000 0000
1	-	1	00 0000 0001
\downarrow	-	\	\downarrow
1022	-	1	11 1111 1110
1023	3.165	1	11 1111 1111
Overflow	> 3.165	0	11 1111 1111

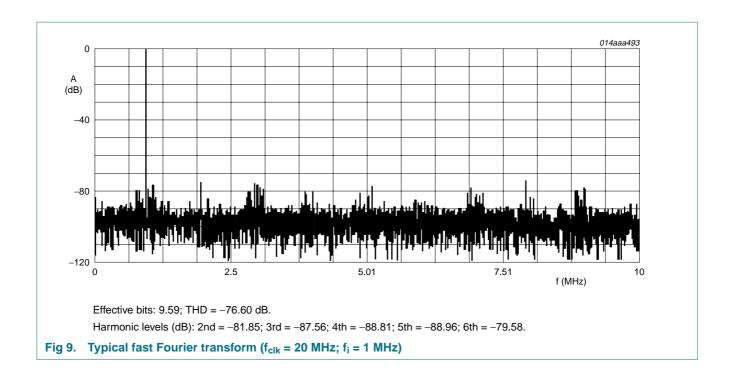


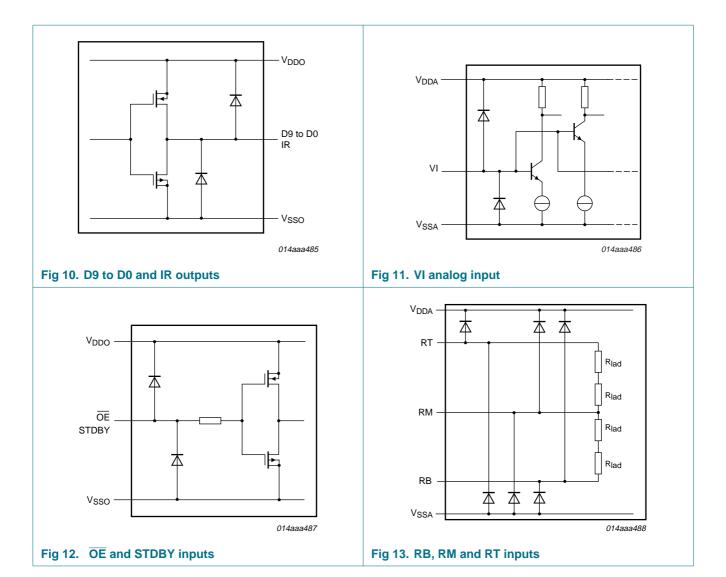


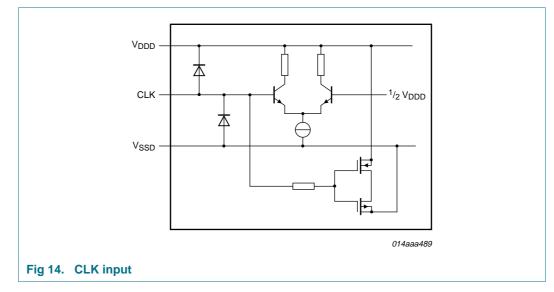






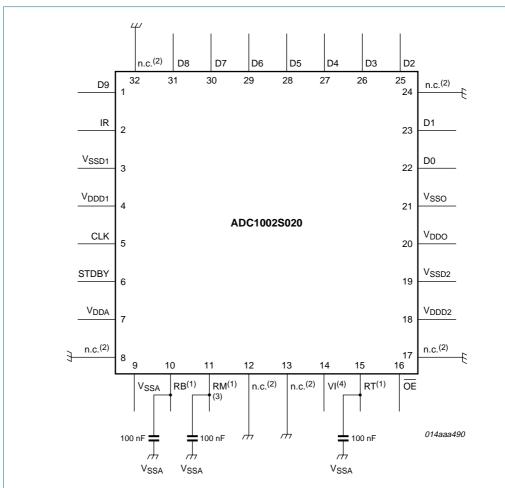






12. Application information

12.1 Application diagram



The analog and digital supplies should be separated and decoupled.

The external voltage reference generator must be built in such a way that a good supply voltage ripple rejection is achieved with respect to the LSB value. Eventually, the reference ladder voltages can be derived from a well regulated V_{DDA} supply through a resistor bridge and a decoupling capacitor.

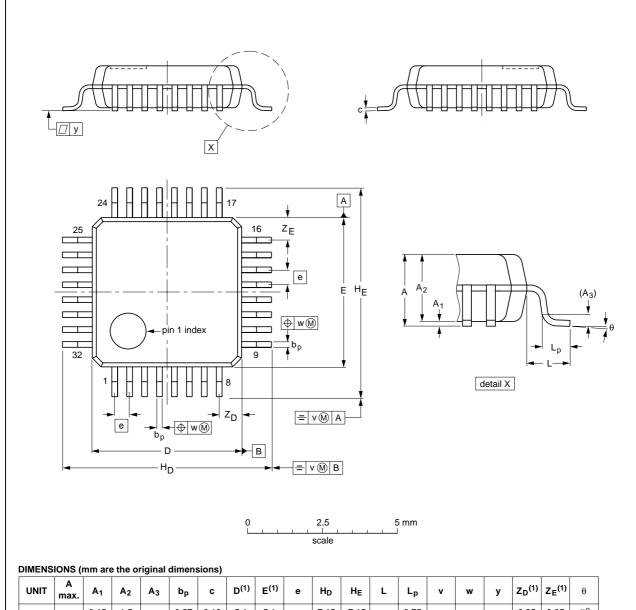
- (1) RB, RM and RT are decoupled to $V_{\mbox{\footnotesize SSA}}$
- (2) Pins 8, 12, 13, 17, 24 and 32 should be connected to the closest ground pin in order to prevent noise influence
- (3) When RM is not used, pin 11 can be left open circuit, avoiding the decoupling capacitor. In any case, pin 11 must not be grounded.
- (4) When the analog input signal is AC coupled, an input bias or a clamping level must be applied to VI input (pin 14).

Fig 15. Application diagram

13. Package outline

LQFP32: plastic low profile quad flat package; 32 leads; body 5 x 5 x 1.4 mm

SOT401-1



UNIT	A max.	A ₁	A ₂	А3	bp	С	D ⁽¹⁾	E ⁽¹⁾	е	H _D	HE	L	Lp	٧	w	у	Z _D ⁽¹⁾	Z _E ⁽¹⁾	θ
mm	1.6	0.15 0.05	1.5 1.3	0.25	0.27 0.17	0.18 0.12	5.1 4.9	5.1 4.9	0.5	7.15 6.85	7.15 6.85	1	0.75 0.45	0.2	0.12	0.1	0.95 0.55	0.95 0.55	7° 0°

Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE			
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE	
SOT401-1	136E01	MS-026				00-01-19 03-02-20	

Fig 16. Package outline SOT401-1 (LQFP32)

ADC1002S020_2 © NXP B.V. 2008. All rights reserved.

14. Revision history

Table 10. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes			
ADC1002S020_2	20080813	Product data sheet	-	ADC1002S020_1			
Modifications: • Corrections made to cross references and note 3 a) in <u>Table 6</u> .							
ADC1002S020_1	20080612	Product data sheet	-	-			

15. Legal information

15.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

15.2 Definitions

Draft — The document is a draft version only. The content is still under internal review and subject to formal approval, which may result in modifications or additions. NXP Semiconductors does not give any representations or warranties as to the accuracy or completeness of information included herein and shall have no liability for the consequences of use of such information.

Short data sheet — A short data sheet is an extract from a full data sheet with the same product type number(s) and title. A short data sheet is intended for quick reference only and should not be relied upon to contain detailed and full information. For detailed and full information see the relevant full data sheet, which is available on request via the local NXP Semiconductors sales office. In case of any inconsistency or conflict with the short data sheet, the full data sheet shall prevail.

15.3 Disclaimers

General — Information in this document is believed to be accurate and reliable. However, NXP Semiconductors does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information.

Right to make changes — NXP Semiconductors reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

Suitability for use — NXP Semiconductors products are not designed, authorized or warranted to be suitable for use in medical, military, aircraft, space or life support equipment, nor in applications where failure or malfunction of an NXP Semiconductors product can reasonably be expected to result in personal injury, death or severe property or environmental

damage. NXP Semiconductors accepts no liability for inclusion and/or use of NXP Semiconductors products in such equipment or applications and therefore such inclusion and/or use is at the customer's own risk.

Applications — Applications that are described herein for any of these products are for illustrative purposes only. NXP Semiconductors makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

Limiting values — Stress above one or more limiting values (as defined in the Absolute Maximum Ratings System of IEC 60134) may cause permanent damage to the device. Limiting values are stress ratings only and operation of the device at these or any other conditions above those given in the Characteristics sections of this document is not implied. Exposure to limiting values for extended periods may affect device reliability.

Terms and conditions of sale — NXP Semiconductors products are sold subject to the general terms and conditions of commercial sale, as published at http://www.nxp.com/profile/terms, including those pertaining to warranty, intellectual property rights infringement and limitation of liability, unless explicitly otherwise agreed to in writing by NXP Semiconductors. In case of any inconsistency or conflict between information in this document and such terms and conditions, the latter will prevail.

No offer to sell or license — Nothing in this document may be interpreted or construed as an offer to sell products that is open for acceptance or the grant, conveyance or implication of any license under any copyrights, patents or other industrial or intellectual property rights.

Quick reference data — The Quick reference data is an extract of the product data given in the Limiting values and Characteristics sections of this document, and as such is not complete, exhaustive or legally binding.

15.4 Trademarks

Notice: All referenced brands, product names, service names and trademarks are the property of their respective owners.

16. Contact information

For more information, please visit: http://www.nxp.com

For sales office addresses, please send an email to: salesaddresses@nxp.com

17. Contents

1	General description
2	Features
3	Applications
4	Quick reference data
5	Ordering information
6	Block diagram 3
7	Pinning information 4
7.1	Pinning
7.2	Pin description
8	Limiting values 5
9	Thermal characteristics 5
10	Characteristics 6
11	Additional information relating to Table 6 9
12	Application information 15
12.1	Application diagram
13	Package outline 16
14	Revision history
15	Legal information
15.1	Data sheet status
15.2	Definitions
15.3	Disclaimers
15.4	Trademarks18
16	Contact information
17	Contents 10

Please be aware that important notices concerning this document and the product(s) described herein, have been included in section 'Legal information'.

